Application/Control No. Applicant(s)/Patent Under Reexamination CHEN ET AL. Examiner Hanh Nguyen Applicant(s)/Patent Under Reexamination CHEN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document-Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5159595	10-1992	Flanagan et al.	370/224
	В	US-6324185 B1	11-2001	Budhraja	370/468
	C	US-6002689	12-1999	Christie et al.	370/401
	D	US-6208657	03-2001	Dendi et al.	370/401
	Ε	US-6643297 B1	11-2003	Sproat et al.	370/498
	·,F	. ປ\$-5809021	09-1998	Diaz et al.	370/364
	O	US-6470018 B1	10-2002	Wiley et al.	370/396
	Ι	US-6041055	03-2000	CHopping	370/391
		US-			
	٦	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	σ					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office PTO-892 (Rev. 01-2001)